





# **Description**

Current Limiting Module (CLM) is a chip type surface mountable device that can protect against both overcurrent and overcharging. It comprises a fuse element to ensure stable operation under normal electrical current and to cut off the current when overcurrent occurs. It also comprises a resistive heating element that could be used in combination with a voltage detecting means, such as IC and FET. When overvoltage is detected, the heating element is electrically excited to generate heat to blow the fuse element to achieve overvoltage protection.

#### **Features**

- · Halogen-free
- Overcharging protection
- · Overcurrent protection
- · Surface mountable · Fast response time

## **Application**

- Notebook
- · Cell phone
- Camera
- Ultrabook

- Tablet PC
- Automotive applications
- Printer
- · Security systems

# **Agency Approval and Environmental Compliance**

Agency	File Number	Regulation	Standard
c <b>FL</b> °us	E331807	Halogen Free	IEC 61249-2-21:2003
Regular Production Surveillance	TA 50428400		

RoHS Directive: Compliance (This product complies with RoHS exemption requirements, since the high melting temperature solder and electronic ceramic parts include Lead.)

#### **Electrical Specifications**

Dout Number	Irated	Cells in	V <sub>max</sub>	I <sub>break</sub>	Vop	Resis	tance	Age Appı	-
Part Number	(A)	series	(V <sub>DC</sub> )	(A)	(V)	$R_{heater}$ $(\Omega)$	$R_{fuse}$ $(m\Omega)$	c <b>FL</b> 'us	TÜVRheinlend
CLM1612P0412	12	1	36	50	3.0 ~ 4.5	0.6 ~ 1.5	1.5 ~ 3.5	✓	✓
CLM1612P0812	12	2	36	50	4.0 ~ 9.0	2.0 ~ 3.2	1.5 ~ 3.5	✓	✓
CLM1612P1212	12	3	36	50	7.4 ~ 13.8	5.7 ~ 9.9	1.5 ~ 3.5	✓	✓
CLM1612P1412	12	4	36	50	10.5 ~ 19.6	11.2 ~ 20.0	1.5 ~ 3.5	✓	✓



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#### **Electrical Characteristics**

Current Capacity	100% x I <sub>rated</sub> No Melting
Cut Time	200% x I <sub>rated</sub> < 1 min
Interrupting Current	5 x I <sub>rated</sub> , power on 5 ms, power off 995 ms, 10000 cycles No Melting
Over Voltage Operation	In operation voltage range, the fusing time is <1min.

## **Note on Electrical Specifications & Characteristics**

#### ■ Vocabulary

 $I_{rated}$  = Current carrying capacity that is measured at 40°C thermal equilibrium condition.

 $I_{break}$  = The current that the fuse element is able to interrupt.  $V_{max}$  = The maximum voltage that can be cut off by fuse.

 $V_{op}$  = Range of operation voltage.

 $R_{\text{heater}}$  = The resistance of the heating element.  $R_{\text{fuse}}$  = The resistance of the fuse element.

Cells in series = Number of battery cells connected in series in the circuit for CLM device to protect.

- Value specified is determined by using the PWB with 2mm\*2oz copper traces, AWG18 covered wire, and 0.6mm glass epoxy PCB.
- Specifications are subject to change without notice.

# **AWARNING**

#### General

- Before and after mounted, the ultrasonic-cleaning or immersion-cleaning must not be done to CLM device. The flux on element would flow, and it would not be satisfied its specification when cleaning is done. In addition, a similar influence happens when the product comes in contact with cleaning-solution. These products after cleaning will not be guaranteed.
- Silicone-based oils, oils, solvents, gels, electrolytes, fuels, acids, and the like will adversely affect the properties of CLM devices, and shall not be used or applied.
- Please Do Not reuse the CLM device removed by the soldering process.
- CLM devices are secondary protection devices and are used solely for sporadic, accidental over-current or over-temperature error condition, and shall NOT be used if or when constant or repeated fault conditions (such fault conditions may be caused by, among others, incorrect pin-connection of a connector) or over-extensive trip events may occur.
- Operation over the maximum rating or other forms of improper use may cause failure, arcing, flame and/or other damage to the CLM devices.
- The performance of CLM devices will be adversely affected if they are improperly used under electronic, thermal and/or mechanical procedures and/or conditions non-conformant to those recommended by manufacturer.
- Customers shall be responsible for determining whether it is necessary to have back-up, failsafe and/or fool-proof protection to avoid or minimize damage that may result from extra-ordinary, irregular function or failure of CLM devices.
- There should be minimum of 0.1mm spacing between CLM and surrounding compounds, to maintain the product characteristics and avoid damage other surrounding compounds.
- This product is designed and manufactured only for general-use of electronics devices. We do not recommend that it is used for the applications Military, Medical and so on which may cause direct damages on life, bodies or properties.



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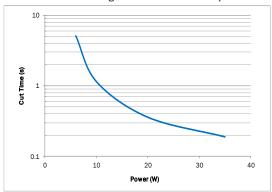


# **Thermal Derating Characteristics**

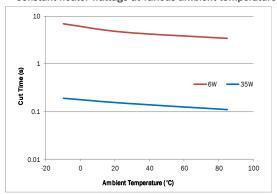
Ambient Temperature (°C)	25	40	60
Recommend Rated Current (A)	13.5	12.0	10.0

# **Cut Time by Heater Operation**

■ Various heater wattage at 25°C ambient temperature.

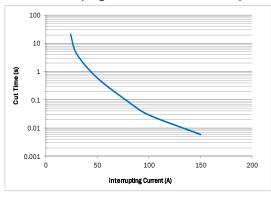


■ Constant heater wattage at various ambient temperature.

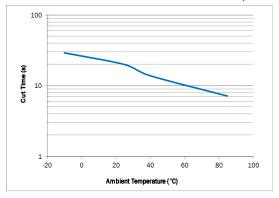


# **Cut Time by Current Operation**

■ Various interrupting current at 25°C ambient temperature.

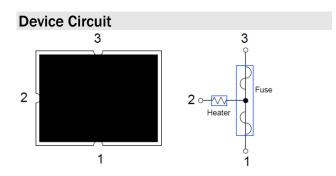


■ Constant 2x rated current at various ambient temperature.

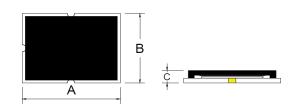


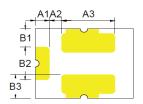
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# **Physical Dimensions (mm.)**





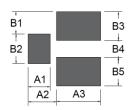
Α	4.00 ± 0.2
В	$3.00 \pm 0.3$
С	0.90 max
A1	$0.58 \pm 0.1$
A2	$0.50 \pm 0.1$
А3	$2.20 \pm 0.1$

B1	0.80 ± 0.1
B2	$1.44 \pm 0.1$
В3	$1.03 \pm 0.1$

# **Environmental Specifications**

Storage Temperature	0~35°C,≦70%RH
	Shelf life: 1 year
Operating Temperature	-10°C to +65 °C
Hat Danning Aging	100±5°C, 250 hours
Hot Passive Aging	No structural damage and functional failure
Humidity Aging	60°C±2°C, 90~95%R.H. 250 hours
	No structural damage and functional failure
Cold Passive Aging	-20±3°C, 500 hours
Cold Passive Aging	No structural damage and functional failure
	MIL-STD-202 Method 107G
Thermal Shock	+125°C /-55°C, 100 times
	No structural damage and functional failure

# **Board and Solder Layout Recommend (mm)**

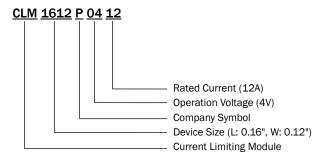


Material	Glass Epoxy PCB
Base Thickness	0.6mm
Copper Thickness	0.07mm
Covered Wire	AWG18

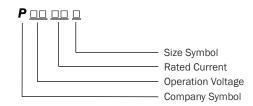
A1	1.20 ± 0.1
A2	$1.55 \pm 0.1$
А3	$2.40 \pm 0.1$

B1	1.20 ± 0.1
B2	$1.60 \pm 0.1$
В3	1.55 ± 0.1
B4	$0.90 \pm 0.1$
B5	1.55 ± 0.1

## **Part Number System**



## **Part Marking System**

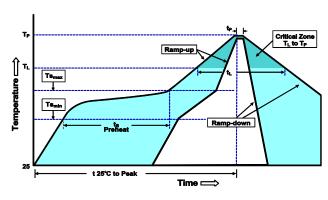




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# **Soldering Parameters**

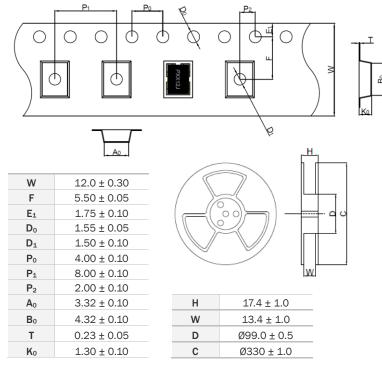


Average Ramp-Up Rate (Ts <sub>max</sub> to T <sub>P</sub> )	3°C/second max.
Preheat	
-Temperature Min (Ts <sub>min</sub> )	150°C
-Temperature Max (Ts <sub>max</sub> )	200°C
-Time (Ts <sub>min</sub> to Ts <sub>max</sub> )	60-120 seconds
Time maintained above:	
-Temperature (T <sub>L</sub> )	217°C
-Time (t <sub>L</sub> )	60-105 seconds
Peak Temperature (T <sub>P</sub> )	255°C
Time within 5°C of actual Peak	
Temperature (t <sub>P</sub> )	5 seconds max.
Ramp-Down Rate	6°C /second max.
Time 25°C to Peak Temperature	8 minutes max.

Note 1: The temperature shown above is the top-side surface temperature of the device.

Note 2: If the soldering temperature profile deviates from the recommended profile, devices may not meet the performance requirements

# Tape & Reel Specification (mm.)



## **Packaging Quantity**

Part Number	Tape & Reel Quantity
CLM1612PXX12	5000



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